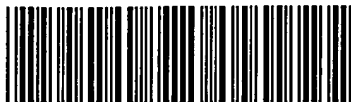


Search Notes

Application/Control No.

10/673,247

Examiner

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Applicant(s)/Patent under
Reexamination

YAMAKAWA ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	717	6/14/2006	BT
438	722	6/14/2006	BT
438	736	6/14/2006	BT
438	742	6/14/2006	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	6/14/2006	BT